

SN5474, SN54LS74A, SN54S74, SN7474, SN74LS74A, SN74S74

SDLS119 DUAL D-TYPE POSITIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET AND CLEAR

DECEMBER 1983 — REVISED MARCH 1988

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

description

These devices contain two independent D-type positive-edge-triggered flip-flops. A low level at the preset or clear inputs sets or resets the outputs regardless of the levels of the other inputs. When preset and clear are inactive (high), data at the D input meeting the setup time requirements are transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold time interval, data at the D input may be changed without affecting the levels at the outputs.

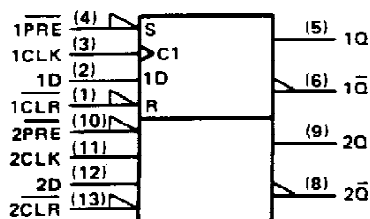
The SN54' family is characterized for operation over the full military temperature range of -55°C to 125°C . The SN74' family is characterized for operation from 0°C to 70°C .

FUNCTION TABLE

INPUTS				OUTPUTS	
PRE	CLR	CLK	D	Q	\bar{Q}
L	H	X	X	H	L
H	L	X	X	L	H
L	L	X	X	H^{\dagger}	H^{\dagger}
H	H	\uparrow	H	H	L
H	H	\uparrow	L	L	H
H	H	L	X	Q_0	\bar{Q}_0

\dagger The output levels in this configuration are not guaranteed to meet the minimum levels in V_{OH} if the lows at preset and clear are near V_{IL} maximum. Furthermore, this configuration is nonstable; that is, it will not persist when either preset or clear returns to its inactive (high) level.

logic symbol \ddagger

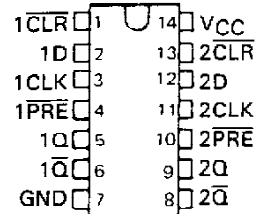


\ddagger This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

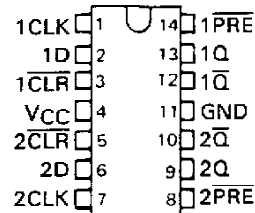
SN5474 . . . J PACKAGE
SN54LS74A, SN54S74 . . . J OR W PACKAGE
SN7474 . . . N PACKAGE
SN74LS74A, SN74S74 . . . D OR N PACKAGE

(TOP VIEW)



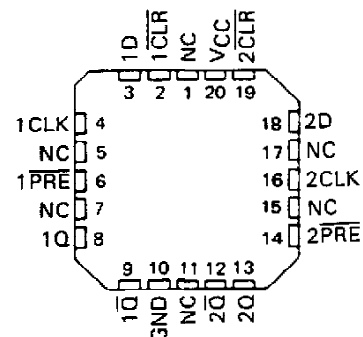
SN5474 . . . W PACKAGE

(TOP VIEW)



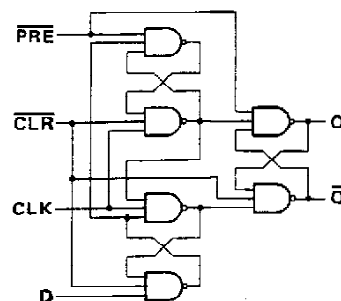
SN54LS74A, SN54S74 . . . FK PACKAGE

(TOP VIEW)



NC - No internal connection

logic diagram (positive logic)



PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

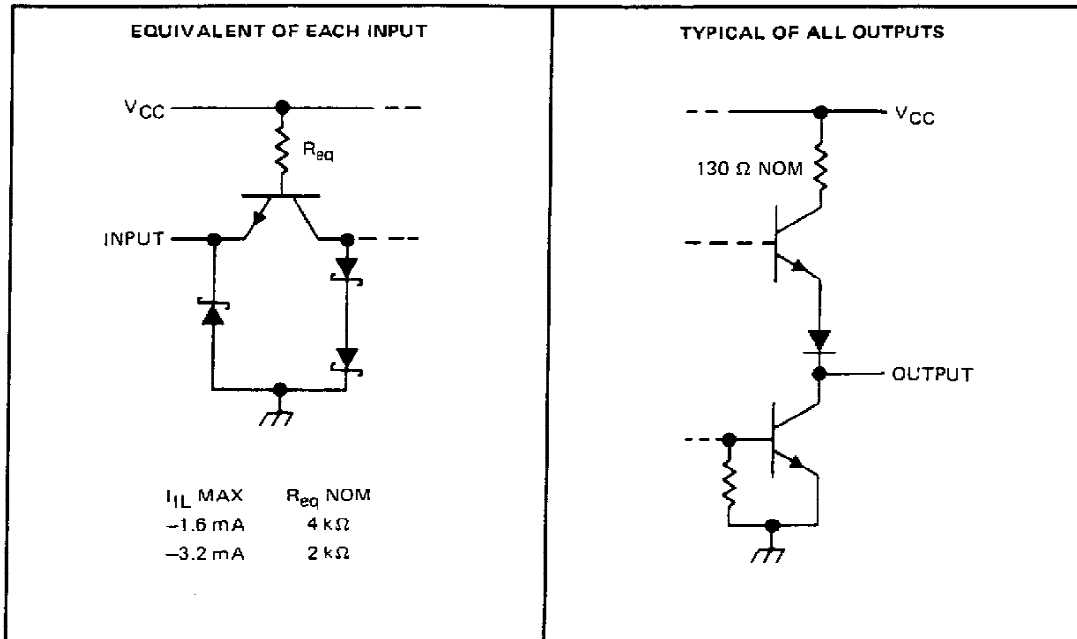
TEXAS
INSTRUMENTS

POST OFFICE BOX 655012 • DALLAS, TEXAS 75265

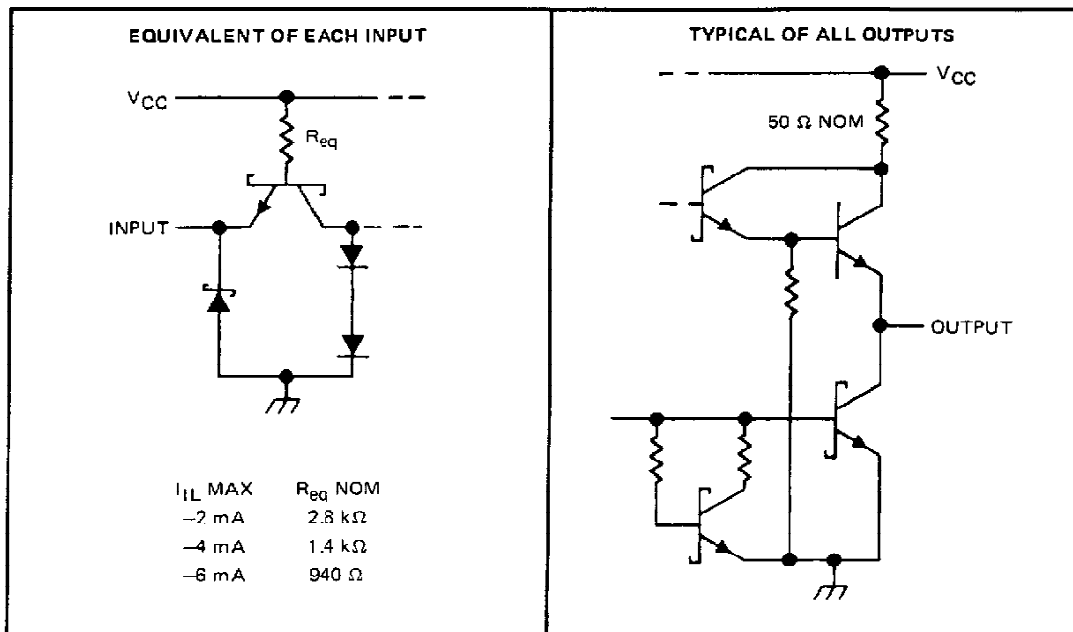
SN5474, SN7474, SN54S74, SN74S74
DUAL D-TYPE POSITIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET AND CLEAR

schematics of inputs and outputs

74



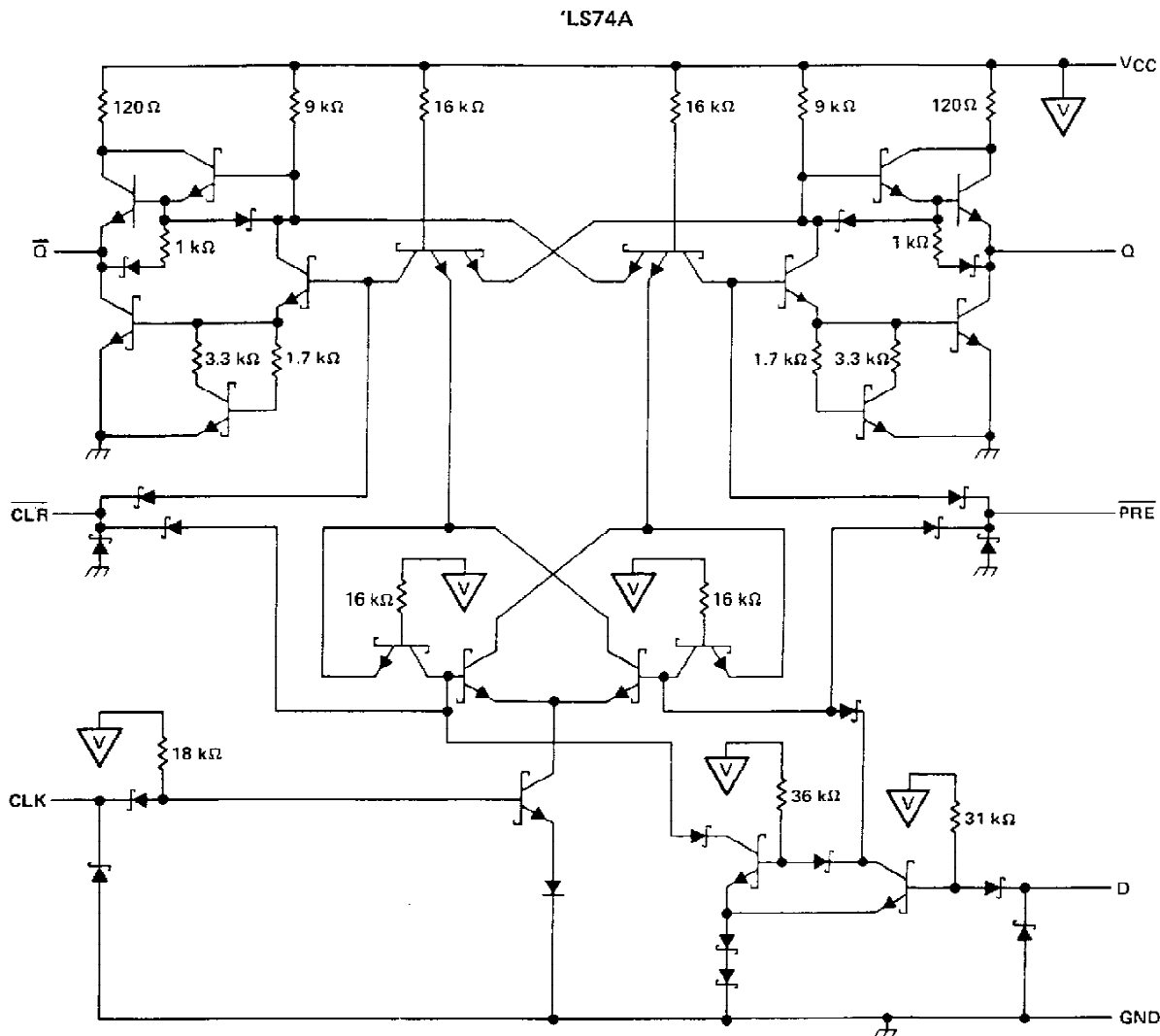
'S74



**SN5474, SN54LS74A, SN54S74,
SN7474, SN74LS74A, SN74S74**

DUAL D-TYPE POSITIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET AND CLEAR

schematic



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1)	7 V
Input voltage: '74, 'S74	5.5 V
'LS74A	7 V
Operating free-air temperature range: SN54'	-55°C to 125°C
SN74'	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.



POST OFFICE BOX 655012 • DALLAS, TEXAS 75265

SN5474, SN7474

DUAL D-TYPE POSITIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET AND CLEAR

recommended operating conditions

		SN5474			SN7474			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC}	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V _{IH}	High-level input voltage	2			2			V
V _{IL}	Low-level input voltage				0.8			V
I _{OH}	High-level output current				-0.4			mA
I _{OL}	Low-level output current				16			mA
t _w	Pulse duration	CLK high		30	30		ns	
		CLK low		37	37			
		PRE or CLR low		30	30			
t _{su}	Input setup time before CLK †	20			20			ns
t _h	Input hold time-data after CLK †	5			5			ns
T _A	Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†	SN5474			SN7474			UNIT
		MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V _{IK}	V _{CC} = MIN, I _I = -12 mA	-1.5			-1.5			V
V _{OH}	V _{CC} = MIN, V _{IH} = 2 V, V _{IL} = 0.8 V, I _{OH} = -0.4 mA	2.4	3.4		2.4	3.4		V
V _{OL}	V _{CC} = MIN, V _{IH} = 2 V, V _{IL} = 0.8 V, I _{OL} = 16 mA		0.2	0.4		0.2	0.4	V
I _I	V _{CC} = MAX, V _I = 5.5 V	1			1			mA
I _{IH}	D	40			40			μA
	CLR	120			120			
	All Other	80			80			
I _{IL}	D	-1.6			-1.6			mA
	PRE‡	-1.6			-1.6			
	CLR‡	-3.2			-3.2			
	CLK	-3.2			-3.2			
I _{OS} ‡	V _{CC} = MAX	-20		-57	-18		-57	mA
I _{CC} #	V _{CC} = MAX, See Note 2		8.5	15		8.5	15	mA

†For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡All typical values are at V_{CC} = 5 V, T_A = 25°C.

§Clear is tested with preset high and preset is tested with clear high.

¶Not more than one output should be shown at a time.

#Average per flip-flop.

NOTE 2: With all outputs open, I_{CC} is measured with the Q and \bar{Q} outputs high in turn. At the time of measurement, the clock input is grounded.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f _{max}			R _L = 400 Ω, C _L = 15 pF	15	25		MHz
‡PLH	$\overline{\text{PRE}}$ or $\overline{\text{CLR}}$	Q or \bar{Q}				25	ns
‡PHL						40	ns
‡PLH	CLK	Q or \bar{Q}			14	25	ns
‡PHL					20	40	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

TEXAS
INSTRUMENTS

POST OFFICE BOX 655012 • DALLAS, TEXAS 75265

SN54LS74A, SN74LS74A

DUAL D-TYPE POSITIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET AND CLEAR

recommended operating conditions

		SN54LS74A			SN74LS74A			UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX		
V_{CC}	Supply voltage	4.5	b	5.5	4.75	5	5.25	V	
V_{IH}	High-level input voltage	2			2			V	
V_{IL}	Low-level input voltage			0.7			0.8	V	
I_{OH}	High-level output current			-0.4			-0.4	mA	
I_{OL}	Low-level output current			4			8	mA	
f_{clock}	Clock frequency	0		25	0		25	MHz	
t_w	Pulse duration	CLK high		25	25			ns	
		PRE or CLR low		25	25				
t_{su}	Setup time-before CLK \uparrow	High-level data		20	20			ns	
		Low-level data		20	20				
t_h	Hold time-data after CLK \uparrow	5		5				ns	
T_A	Operating free-air temperature	-55		125		0		70	$^{\circ}$ C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS [†]	SN54LS74A			SN74LS74A			UNIT
			MIN	TYP [‡]	MAX	MIN	TYP [‡]	MAX	
V_{IK}		$V_{CC} = \text{MIN}, I_I = -18 \text{ mA}$	-1.5			-1.5			V
V_{OH}		$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, V_{IL} = \text{MAX}, I_{OH} = -0.4 \text{ mA}$	2.5	3.4		2.7	3.4		V
V_{OL}		$V_{CC} = \text{MIN}, V_{IL} = \text{MAX}, V_{IH} = 2 \text{ V}, I_{OL} = 4 \text{ mA}$	0.25	0.4		0.25	0.4		V
		$V_{CC} = \text{MIN}, V_{IL} = \text{MAX}, V_{IH} = 2 \text{ V}, I_{OL} = 8 \text{ mA}$				0.35	0.5		
I_I	D or CLK	$V_{CC} = \text{MAX}, V_I = 7 \text{ V}$	0.1			0.1			mA
	CLR or PRE		0.2			0.2			
I_{IH}	D or CLK	$V_{CC} = \text{MAX}, V_I = 2.7 \text{ V}$	20			20			μ A
	CLR or PRE		40			40			
I_{IL}	D or CLK	$V_{CC} = \text{MAX}, V_I = 0.4 \text{ V}$	-0.4			-0.4			mA
	CLR or PRE		-0.8			-0.8			
I_{OS}^{\S}		$V_{CC} = \text{MAX},$ See Note 4	-20	-100		-20	-100		mA
I_{CC} (Total)		$V_{CC} = \text{MAX},$ See Note 2	4	8		4	8		mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡] All typical values are at $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}$.

[§] Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

NOTE 2: With all outputs open, I_{CC} is measured with the Q and \bar{Q} outputs high in turn. At the time of measurement, the clock input is grounded.

NOTE 4: For certain devices where state commutation can be caused by shorting an output to ground, an equivalent test may be performed with $V_O = 2.25 \text{ V}$ and 2.125 V for the 54 family and the 74 family, respectively, with the minimum and maximum limits reduced to one half of their stated values.

switching characteristics, $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}$ (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN	TYP	MAX	UNIT
f_{max}			$R_L = 2 \text{ k}\Omega,$	$C_L = 15 \text{ pF}$	25	33		MHz
t_{PLH}	$\overline{\text{CLR}}, \overline{\text{PRE}}$ or CLK	Q or \bar{Q}			13	25		ns
t_{PHL}					25	40		ns

Note 3: Load circuits and voltage waveforms are shown in Section 1.


TEXAS
INSTRUMENTS

POST OFFICE BOX 655012 • DALLAS, TEXAS 75265

SN54S74, SN74S74

DUAL D-TYPE POSITIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET AND CLEAR

recommended operating conditions

		SN54S74			SN74S74			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V_{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.8			0.8	V
I_{OH}	High-level output current			-1			-1	mA
I_{OL}	Low-level output current			20			20	mA
t_w	Pulse duration	CLK high	6		6			ns
		CLK low	7.3		7.3			
		\overline{CLR} or \overline{PRE} low	7		7			
t_{su}	Setup time, before CLK \uparrow	High-level data	3		3			ns
		Low-level data	3		3			
t_h	Input hold time - data after CLK \uparrow	2			2			ns
T_A	Operating free-air temperature	-55		125	0		70	$^{\circ}C$

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS [†]	SN54S74			SN74S74			UNIT
		MIN	TYP [‡]	MAX	MIN	TYP [‡]	MAX	
V_{IK}	$V_{CC} = \text{MIN.}$, $I_I = -18 \text{ mA.}$			-1.2			-1.2	V
V_{OH}	$V_{CC} = \text{MIN.}$, $V_{IH} = 2 \text{ V.}$, $V_{IL} = 0.8 \text{ V.}$, $I_{OH} = -1 \text{ mA}$	2.5	3.4		2.7	3.4		V
V_{OL}	$V_{CC} = \text{MIN.}$, $V_{IH} = 2 \text{ V.}$, $V_{IL} = 0.8 \text{ V.}$, $I_{OL} = 20 \text{ mA}$			0.5			0.5	V
I_I	$V_{CC} = \text{MAX.}$, $V_I = 5.5 \text{ V}$			1			1	mA
I_{IH}	D			50			50	μA
	\overline{CLR}	$V_{CC} = \text{MAX.}$, $V_I = 2.7 \text{ V}$		150			150	
	\overline{PRE} or CLK			100			100	
I_{IL}	D			-2			-2	mA
	\overline{CLR} [†]	$V_{CC} = \text{MAX.}$, $V_I = 0.5 \text{ V}$		-6			-6	
	\overline{PRE} [†]			-4			-4	
	CLK			-4			-4	
I_{OS} [§]	$V_{CC} = \text{MAX.}$	-40		-100	-40		-100	mA
I_{CC} [#]	$V_{CC} = \text{MAX.}$, See Note 2		15	25		15	25	mA

[†]For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡]All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}C$.

[§]Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

[†]Clear is tested with preset high and preset is tested with clear high.

[#]Average per flip-flop.

NOTE 2: With all outputs open, I_{CC} is measured with the Q and \overline{Q} outputs high in turn. At the time of measurement, the clock input is grounded.

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}C$ (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f_{max}				75	110		MHz
t_{PLH}	\overline{PRE} or \overline{CLR}	Q or \overline{Q}	$R_L = 280 \Omega$, $C_L = 15 \text{ pF}$		4	6	ns
t_{PHL}	\overline{PRE} or \overline{CLR} (CLK high)	\overline{Q} or Q		9	13.5		ns
	\overline{PRE} or \overline{CLR} (CLK low)			5	8		
t_{PLH}	CLK	Q or \overline{Q}			6	9	ns
t_{PHL}					6	9	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

TEXAS
INSTRUMENTS

POST OFFICE BOX 655012 • DALLAS, TEXAS 75265

IMPORTANT NOTICE

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.

IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.